


<b>Search Notes</b>  	<b>Application/Control No.</b>  10577453	<b>Applicant(s)/Patent Under Reexamination</b>  VAINIO ET AL.
	<b>Examiner</b>  MARCOS BATISTA	<b>Art Unit</b>  4134

SEARCHED			
Class	Subclass	Date	Examiner
455	209	3/11/2008	mb
370	286	3/11/2008	mb

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Steve D'Aghosta	3/11/2008	mb
Consulted w/ lab TA Yogesh Aggarwal	3/11/2008	mb
Consulted with Lun-Yi Lao	3/11/2008	mb
Inventor's Name Search	3/11/2008	mb
East Search	3/10/2008	mb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner